
Bringing statistical methods for reliability testing in line with the computer age

This volume presents state-of-the-art, computer-based statistical methods for reliability data analysis and test planning for industrial products. *Statistical Methods for Reliability Data* updates and improves established techniques as it demonstrates how to apply the new graphical, numerical, or simulation-based methods to a broad range of models encountered in reliability data analysis. It includes methods for planning reliability studies and analyzing degradation data, simulation methods used to complement large-sample asymptotic theory, general likelihood-based methods of handling arbitrarily censored data and truncated data, and more. In this book, engineers and statisticians in industry and academia will find:

- A wealth of information and procedures developed to give products a competitive edge
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An essential resource for practitioners involved in product reliability and design decisions, *Statistical Methods for Reliability Data* is also an excellent textbook for on-the-job training courses, and for university courses on applied reliability data analysis at the graduate level.

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WILEY-INTERSCIENCE

John Wiley & Sons, Inc.

Professional, Reference and Trade Group

605 Third Avenue, New York, N.Y. 10158-0012

New York • Chichester • Weinheim

Brisbane • Singapore • Toronto

ISBN 978-0-471-14328-4



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